Sheet 1 of 1 **FORM PTO-1449** ATTY. DOCKET NO. SERIAL NO. SHP-PT077 10/612,133 U.S. DEPARTMENT OF COMMERCE **APPLICANT** PATENT AND TRADEMARK OFFICE Miles et al. INFORMATION DISCLOSURE **GROUP FILING DATE** STATEMENT BY APPLICANT June 2, 2003 2878 (Use several sheets if necessary) **U.S. PATENT DOCUMENTS** EXAMINER FILING DATE IF APPROPRIATE INITIAL DOCUMENT NUMBER DATE NAME CLASS SUBCLASS 2 5 7 7 04/1998 AΑ 4 2 324 754 AB 6 1 7 2 458 5 0 6 01/2001 324 FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS YES NO AC 0 4 0 3 1 01/1991 Europe 0 5 5 07/1993 AD 1 8 1 4 Europe 8 2 9 0 1 1 8 05/1996 Japan OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) DATE CONSIDERED EXAMINER

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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			U.S. PATENT	DOCUMENTS		_	_	
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OXL	AF	6,008,489	12/1999	Elings et al.	250	23.4		
TXI	AG	6,220,084	04/2001	Chen et al.	73	105		
(XL	AH	6,404,207	06/2002	Bhushan	324	671		
(XL	Al	2002/0097046	07/2002	Kitamura	324	244		
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							TRANSLATION	
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77 l	AK Tran et al., "Zeptofarad (10-21F) Resolution Capacitance Sensor for Scanning Capacitance Microscopy," American Institute of Physics, June 2001 (2001-06), Vol. 72, no. 6, pages 2618-2623							
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